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Application/Control	No.

10541028

Examiner

DAVID H CHU

Applicant(s)/Patent Under Reexamination SUKENO ET AL.

Art Unit 2628

ORIGINAL						INTERNATIONAL CLASSIFICATION										
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/DAVID H CHU/ Examiner.Art Unit 2628 (Assistant Examiner)	12/20/2008 (Date)	Total Claims Allowed:			
/XIAO M. WU/ Supervisory Patent Examiner, Art Unit 2628 (Primary Examiner)	(Date)	O.G. Print Claim(s)	O.G. Print Figure		